Special Issue

Light Management for Optoelectronics

Message from the Guest Editors

Light Management for Optoelectronics tries to call the attention of all the scientific community working on the improvement of optoelectronic device performance by means of optimized photon management. The scope could include:

- Interference based anti-reflection coatings (ARC)
- Anti-reflection effects of nano-rough interfaces and effective media
- Light scattering at randomly textured interfaces
- Light scattering at (quasi-)periodic geometries and corresponding production methods
- Resonant light trapping be means of photonic crystals
- Light coupling to waveguide modes in optoelectronic devices.
- Plasmonic nanostructures
- Intermediate reflector layers in multi-junction devices
- Light trapping structures and low temperature processes for light management
- External optical elements for light trapping
- Advanced optical modeling, especially with complex multi-junction configurations
- Characterization and assessment of light management in optoelectronic devices

Guest Editors

Dr. Jürgen Hüpkes

Forschungszentrum Jülich GmbH; Institut für Energie- und Klimaforschung (IEK 5), 52425 Jülich, Germany

Dr. Karsten Bittkau

Forschungszentrum Jülich GmbH; Institut für Energie- und Klimaforschung (IEK 5), 52425 Jülich, Germany

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Applied Sciences
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
applsci@mdpi.com

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

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